NOTES:
1) MATERIAL: SULFUR FREE CADMIUM SELENIDE (CdSe).
2) PITCH POLISH TO TEST PLATE WITHIN POWER AND IRREGULARITY INDICATED.
3) MANUFACTURE PER MIL-O-13830.
4) SURFACE FRINGES = 0.25 FRINGES
5) TEST WAVELENGTH = 0.6328 UM.
6) HIGH EFFICIENCY, NON-THORIUM, AR COATING AT 8-12 MICRONS.

SURFACE | RADIUS | RAD TOL | IRR TOL | C.A DIA
--- | --- | --- | --- | ---
SI | PLANO | 0.0000 | 0.0079 | 1.1811
S2 | PLANO | 0.0000 | 0.0079 | 1.1811

DETAIL - HALF WAVE PLATE A
HALF WAVE PLATE HOLDER

TOLERANCES UNLESS OTHERWISE SPECIFIED
X.XXX = ±0.005
X.XX = ±0.01
X.X = ±0.03
ANGULAR = ±0.2°

QTY | PART NO. | DIM "A" | DESCRIPTION
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2 | IN-CC-MC-540-0001 | 0.0765 | DETAIL - 1.944mm HALF WAVE PLATE
1 | IN-CC-MC-540-0002 | 0.0875 | DETAIL - 2.222mm HALF WAVE PLATE
1 | IN-CC-MC-540-0003 | 0.0656 | DETAIL - 1.667mm HALF WAVE PLATE